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**Analysis is from Venus, Synthesis from Mars**

**Patrick Groeneveld  
Chief Architect, Magma Design Automation  
EDP 2007, Monterey**

# Summary

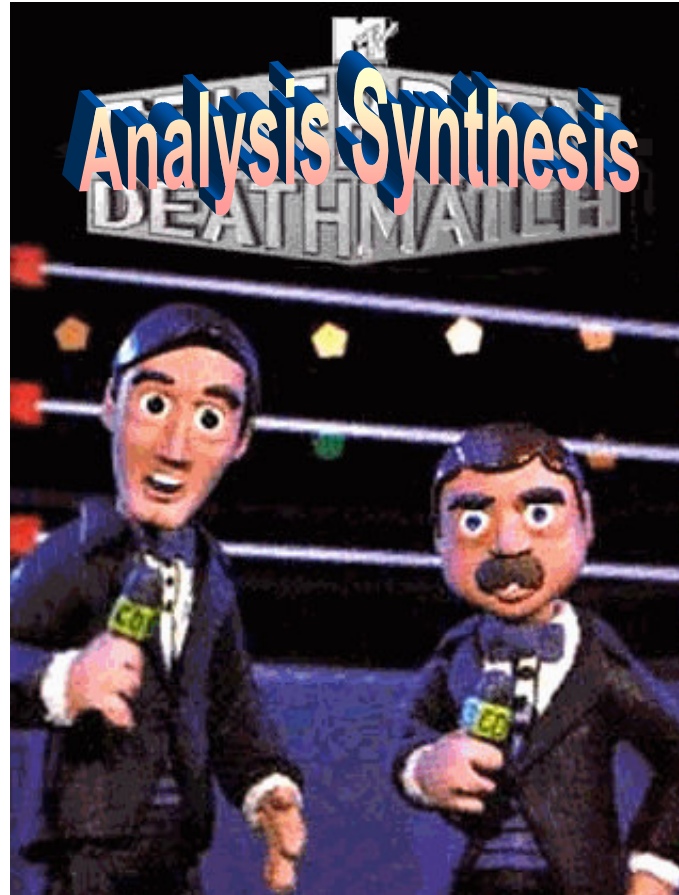
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- **Focus on physical *synthesis* ASIC flow**
  - With given process technology, what can Physical Design Tools to handle DFM&Y?
- **Engineering principles**
- **Engineering a flow that improves Manufacturability and yield**
  - CMP
  - OPC
  - CAA
  - SSTA
- **Recommendations**

# Analysis is from Venus, Synthesis from Mars

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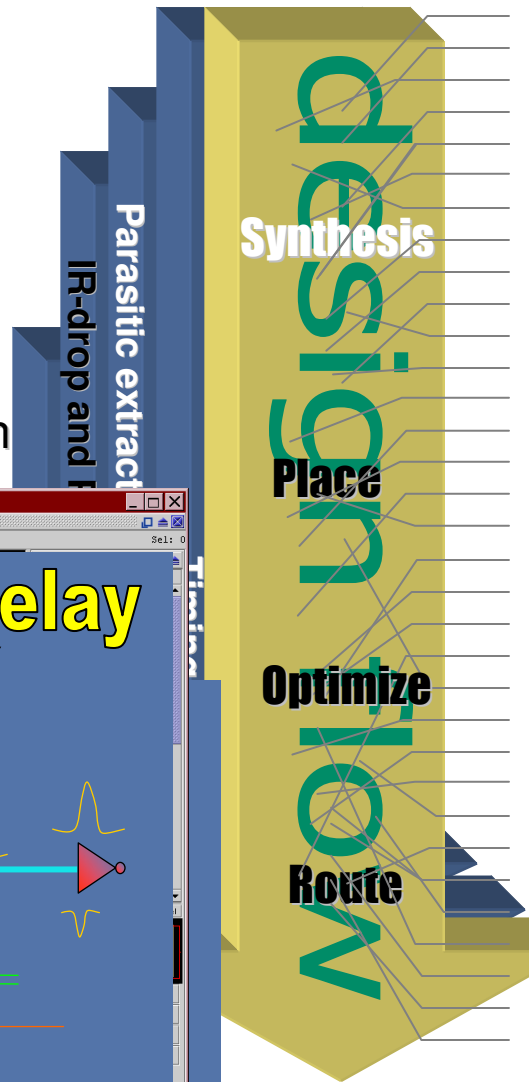
- Analyzes properties
- Many established models.
- Big and slow
- Highly accurate
- Each objective measurable
- Fully automatic
- Can't fix anything



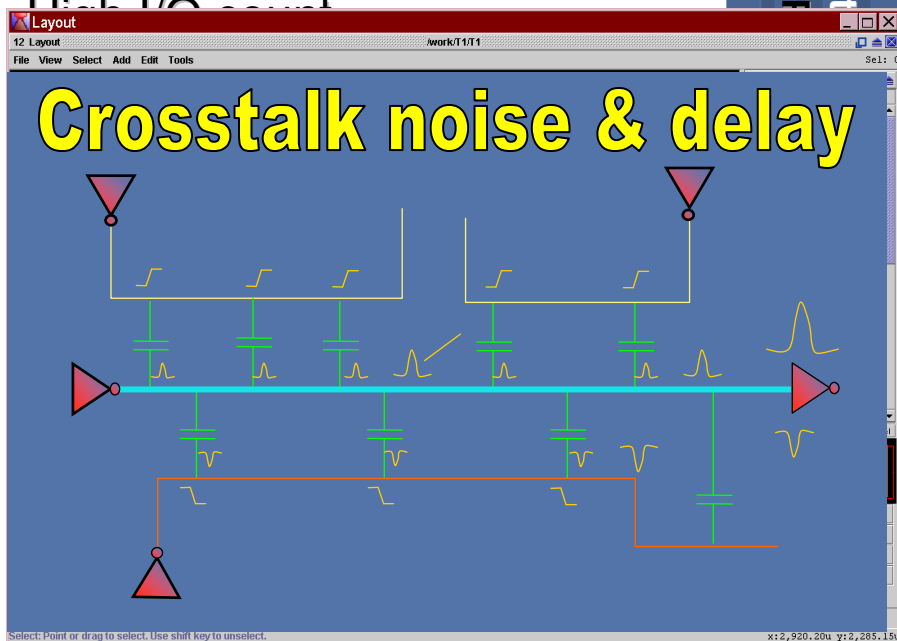
- Synthesizes things
- Very few models/methods used.
- Leaner, Faster
- Very poor accuracy
- Difficult handle multiple objectives.
- Needs manual help
- Is the builder

# The anatomy of a Physical Synthesis flow

Timing closure (parasitic cap.)  
 Routing closure  
 Design scale, concurrent design  
 Testability  
 ECO capability  
 Clock skew  
 Low power requirements  
 IR voltage drop, Electromigration  
 High I/O count



- BIST insertion
- Clock gating
- Hierarchy, Partitioning, design planning
- Flip-chip packaging
- Block/macro placement
- Load buffering
- Mapping for speed
- Noise buffering
- Diode insertion
- Decoupling caps, package design
- Multi-VDD regions
- Large capacity and fast algorithms
- Timing/sizing driven placement
- Gate sizing
- Delay buffering
- Cloning, logic restructuring
- Congestion control
- Useful skew clock synthesis
- Spare cell insertion
- Balanced clock trees
- Antenna-friendly routing, jumper insertion
- Power infrastructure
- Dual-hierarchy support
- Scan chain reordering and routing
- Rip-up and reroute
- Correct-by-construction tools
- Clock shielding
- Wire spacing
- Wire widening
- Dual Vt support
- Filling, slotting, router adaptations
- Wire shielding
- Hold time buffering



# DFM and Yield are important, BUT...

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- **Other objectives are relevant as well**
- **Area (cost)**
  - Bigger area avoids most DFM issues!
- **Timing performance**
  - X-talk
- **Correctness, Testability**
- **Design effort, complexity**
- **Power**

**Must find reasonable trade-off**



# The ABC of a well-engineered IC design flow

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## **A: Avoid**

Detect specific problem patterns early, fix them

- Relies on prediction which
- does not have to be extremely accurate.

## **B: Build**

Synthesize using an algorithm on a simplified model.

- Capture 1st order effect of problem as objective.
- Shoot in the ball park, and hope for the best.

## **C: Correct**

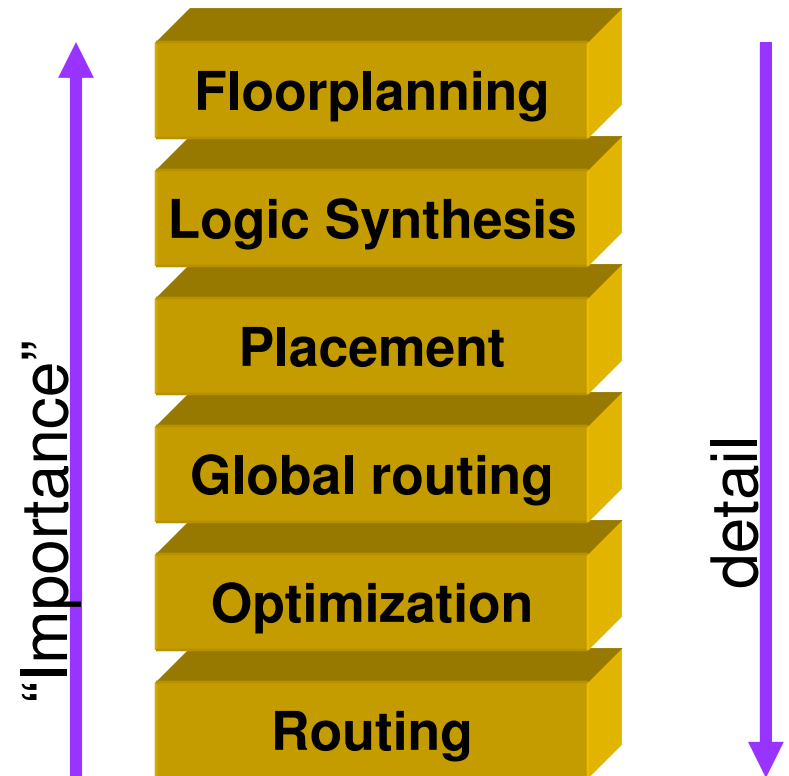
Perform accurate analysis, detect remaining problems and fix any problems by local modifications (ECO).

- This is typically slow and it
- might not work.
- If its real bad, iterate back to step A or B

# Guiding principles during Physical Synthesis

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- **Stepwise refinement**
  - Use a number of build steps, each fixing an objective and adding detail
- **Avoid Correction iteration like the plague**
- **Use *in*accurate analysis**
  - Ballpark is enough, You're far off anyway
- **Keep sign-off levels alive**
  - Despite attacks





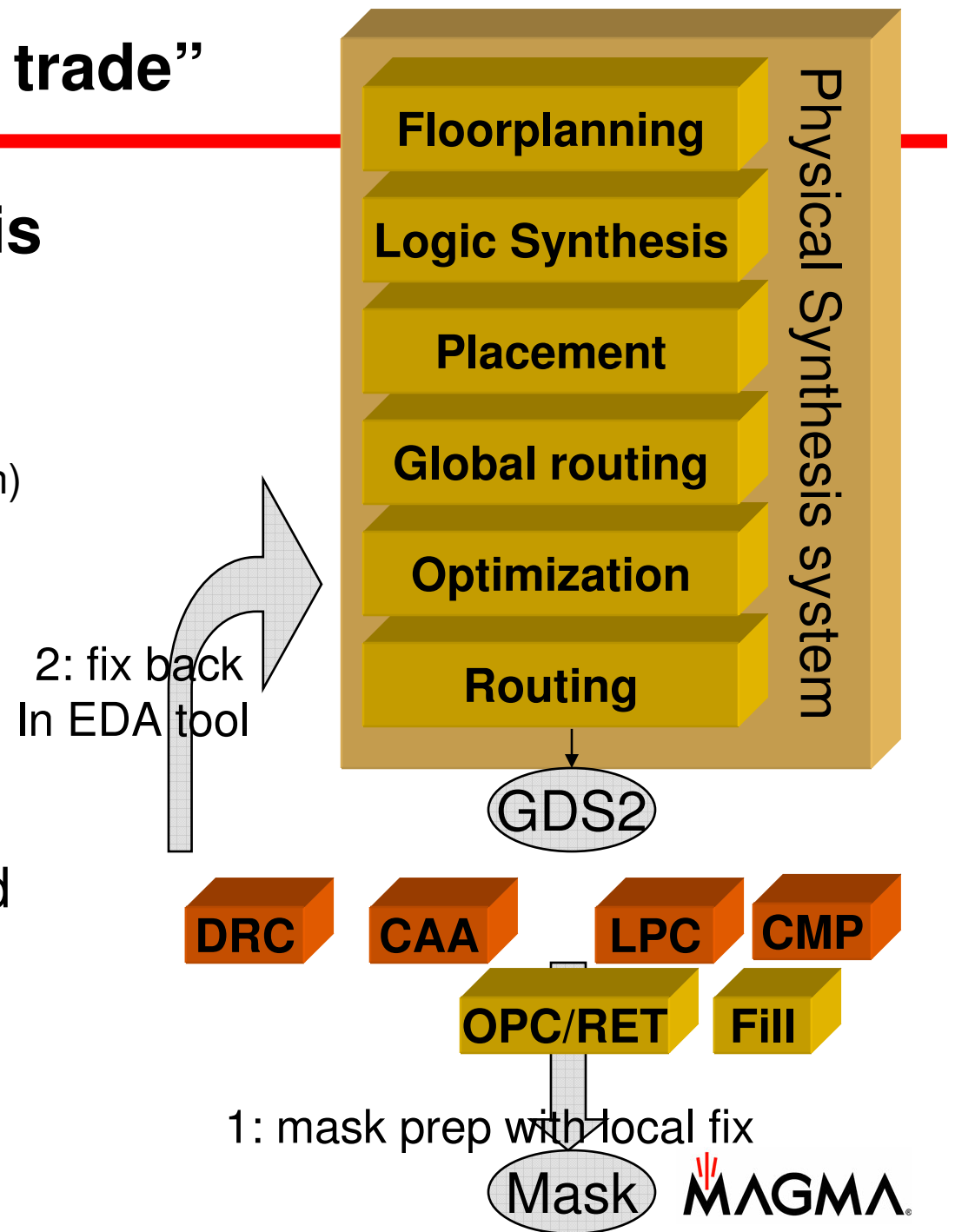
# The tools of the “DFM trade”

- **Layout-level Analysis**

- DRC (Design rule checker)
- CAA (Critical Area Analysis)
- LPC (Litho Shape Simulation)
- CMP (Thickness Simulation)
- SSTA (Statistical Timing)

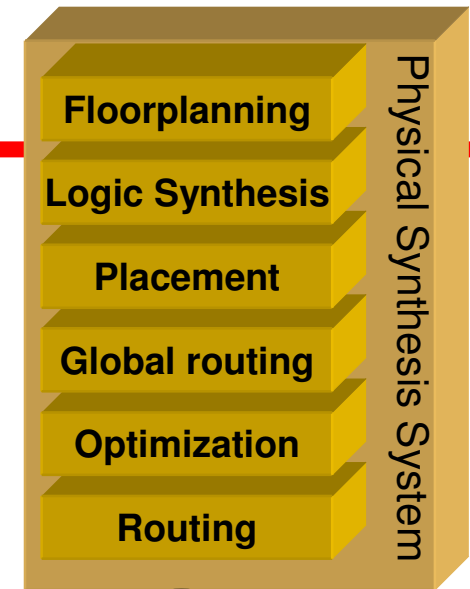
- **Synthesis**

- Pessimism and a
- Bunch of hacks around existing tools...

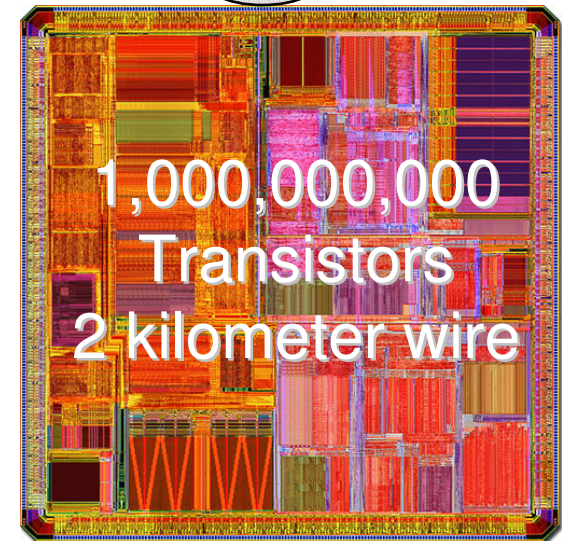


# How much bad news is acceptable?

- ... from your DFM (sign-off) analysis tools?
- < 100 violations
  - Manual fixes are feasible
- < 1000 violations
  - ECO-style fixes, rip-up and reroute
- > 10000 violations:
  - Re-run entire flow, and somehow do it better next time...



GDS2



**Better be 99.9999%**

**Correct by construction!!!**

DRC

CAA

LPC

CMP

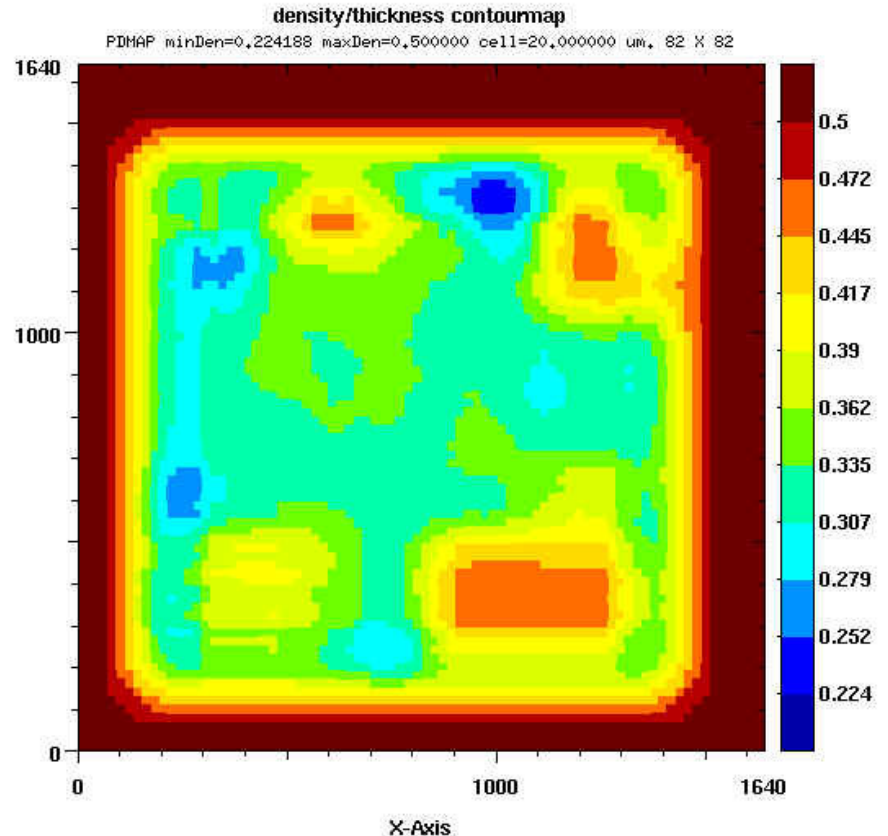
# Avoidance (not patching) is key

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- **Sign-off abstraction levels are needed to avoid costly iteration:**
  - Logic: gates + nets
  - Physical: Standard cells + wires
  - GDS2: transistor pattern + wire pattern
- **Cells = place to hide mask and DFM issues**
  - Must remain rock-solid building blocks
  - This model was driver for Moore's law!
- **Wires = Interconnect mask**
  - Use grid abstraction for wire that ensure 99.9999%

# Problem 1: CMP variation (systematic yield loss)

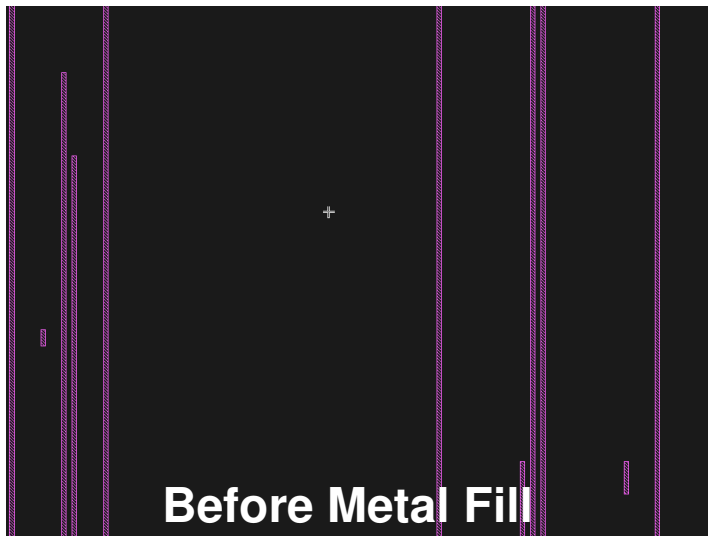
- **Problem:**
  - layout pattern density influences metal thickness, resulting in systematic wire resistance variations or failure.
- **Desired:**
  - keep (local) mask density variation within limits
  - Lower density = lower resistance
- **Simulator:**
  - CMP Thickness simulation tool



# CMP variation: Plans of attack

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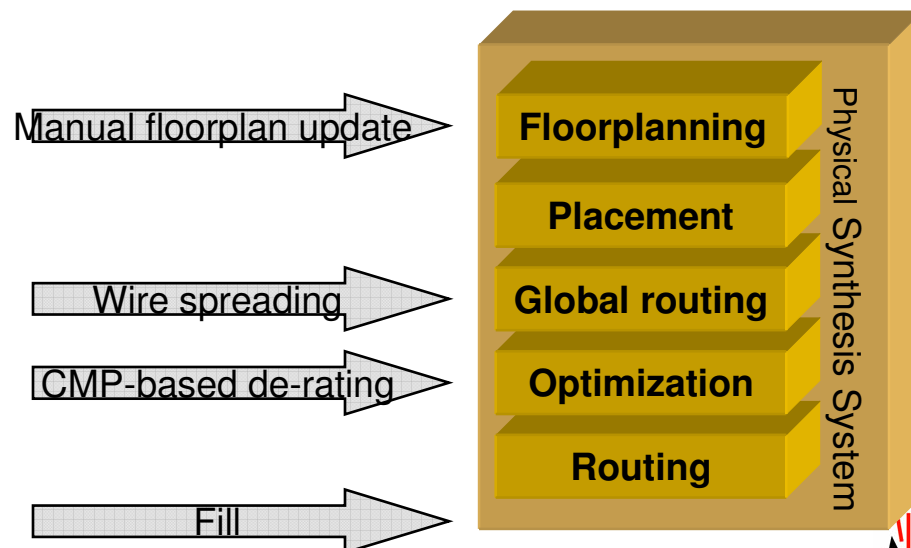
- **1) Metal fill, encoded in layout “density rules”**
  - Reduce effect on delay/timing by ‘double spacing’ wires



- **2) Manual floorplan updates**
- **3) Use fill-friendly power supply mesh pattern**
- **4) Force global router to spread wires even more**
  - This will start to cost wire length and contacts
- **5) Back-annotate density effect on delay into timer**
  - This could reduce pessimism in the delay calculator.

# CMP variation synthesis: Score chart of methods

	How	The good	The bad
Fill insertion	Pre/post GDS2 step	Effective	Adds wire cap. Huge files
Global router wire spreading	Costing global router	Helps other objectives	Not effective, Longer wires
De-rate timer by CMP wire thickness.	Optimization based on congestion data	Reduces pessimism, so smaller gates	Not effective Needs reliable process data.





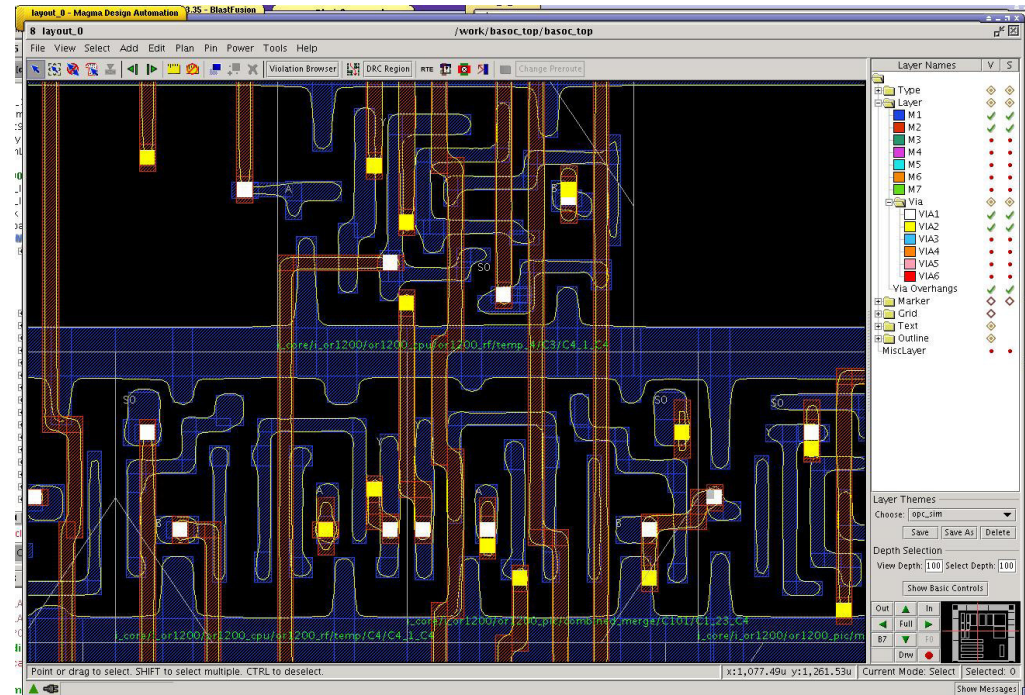
# Problem2: Wire Layout printability (systematic)

- **The problem:**

- What you see != what you get
- Failures, resistance variations.
- Depends on **pattern** in the local neighborhood

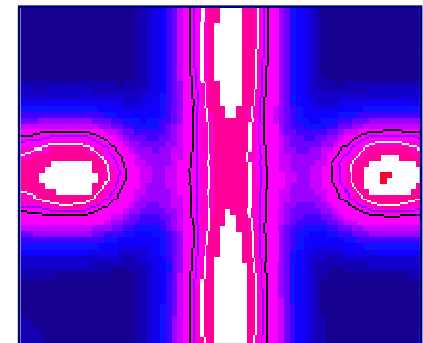
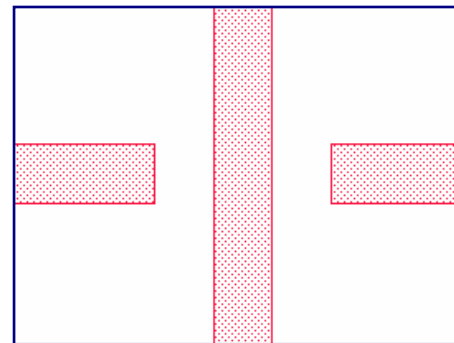
- **Goal:**

- Achieve printability without impairing density and routability too much.



- **Simulator/sign off tools:**

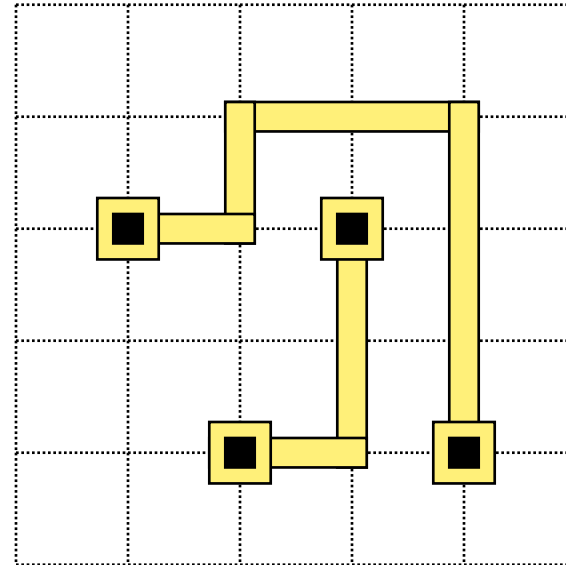
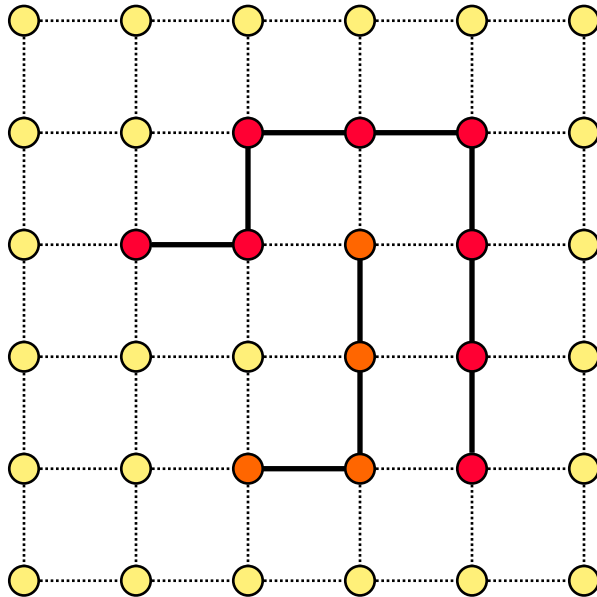
- Pattern matching DRC
- LPC simulator (SLOW!)



# Wire layout printability: router foundation

- **Restrict the type of wire patterns that routers generate.**
  - Encode DRC rules using a regular 'grid graph'

Smaller solution space!

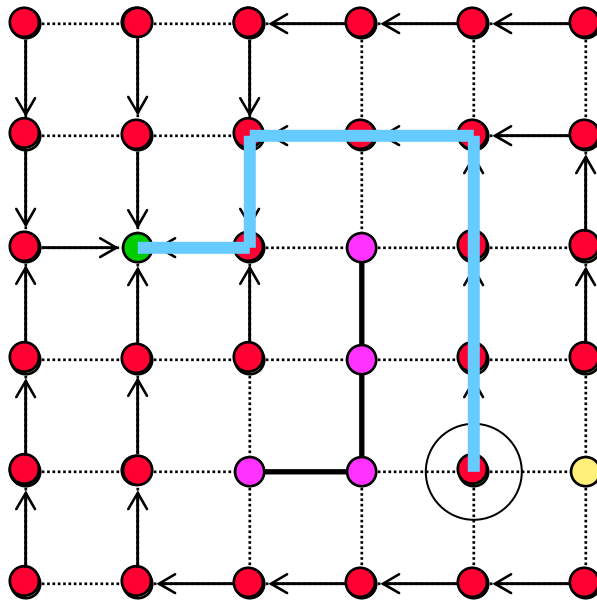


- **How to get printability rules in there?**
  - Local modifications of the grid graph can encode certain design rules, off grid elements



# Workhorse: Dijkstra's algorithm on a grid graph

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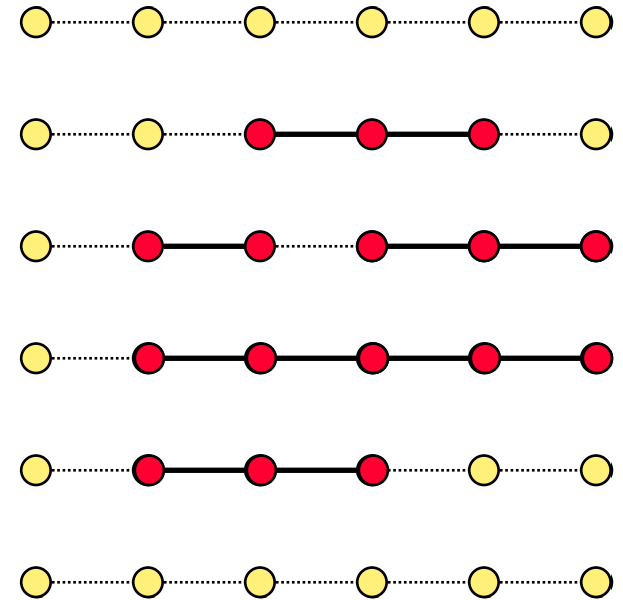


- **The good:**  
Guarantees to find shortest path, if it exists.
- **The bad:**  
Sequential: no guarantees for multiple nets
- **Killer feature:**  
Changing the edge weight can encode preferences.

# Wire Layout printability: plan of attack

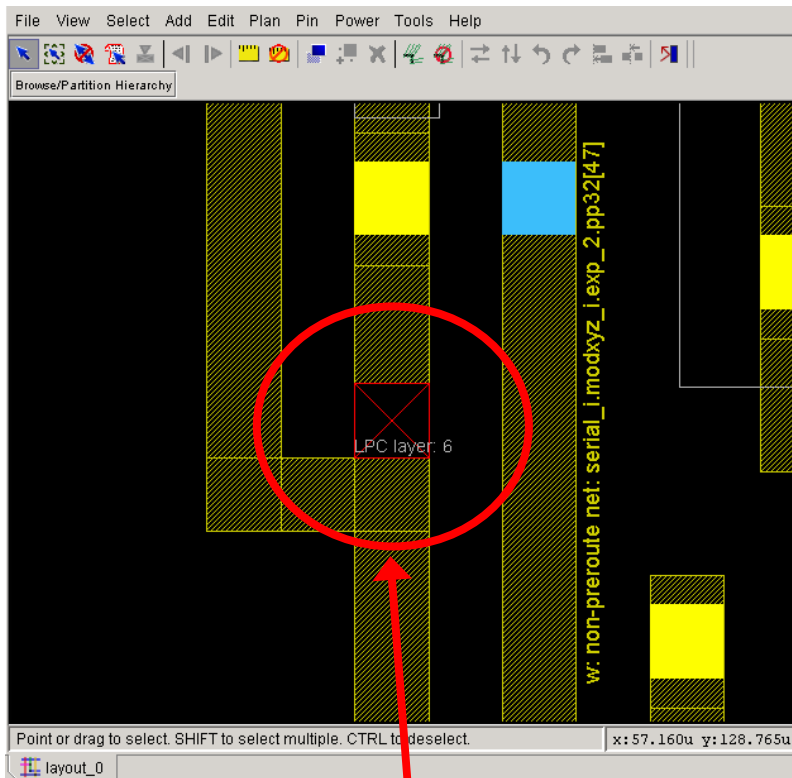
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- **1: Pick proper grid spacing**
  - This is the starting point
- **2: Pre-condition grid landscape**
  - Block likely hot spots
  - Remove non-preferred direction edges
    - Creates lots of extra contacts
- **3: Cost the edges**
  - Make edges around likely hot-spots expensive
- **4: Patterns during path search**
  - Disabling stacked via avoids island problem
  - End-of-line rule compliance
- **5: Post-process routing patterns**
  - Rip-up-and-reroute, small modifications

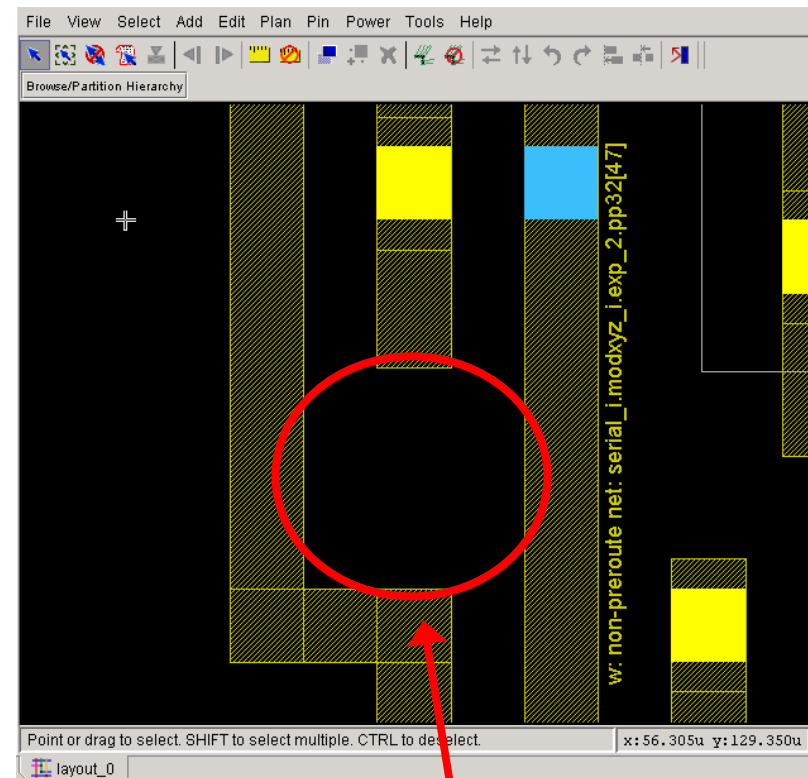


# Litho Hot Spot Optimizations

- Fix method: LPC hot spot resolved by re-routing



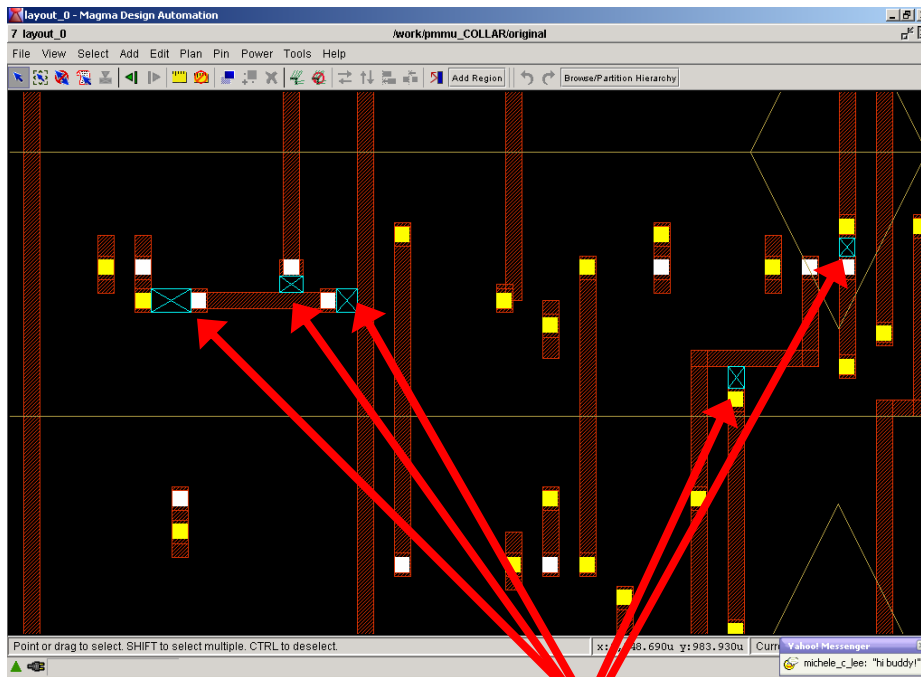
**LPC hot spot**



**Hot spot removed**

# LPC-based post processing

- Litho hot-spots detected using LPC
- Area blocked, and locally re-routed



**Five hot spots**

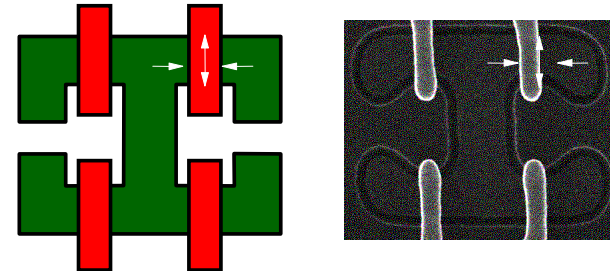


**4 fixed, 1 left**

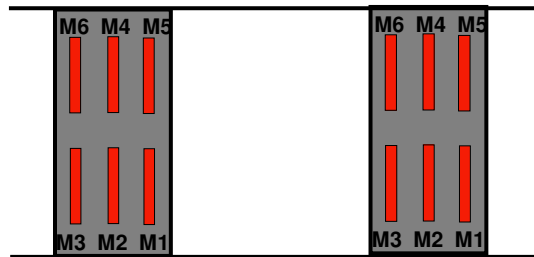
Method is slow and has Limited strength

# Printability of standard cells

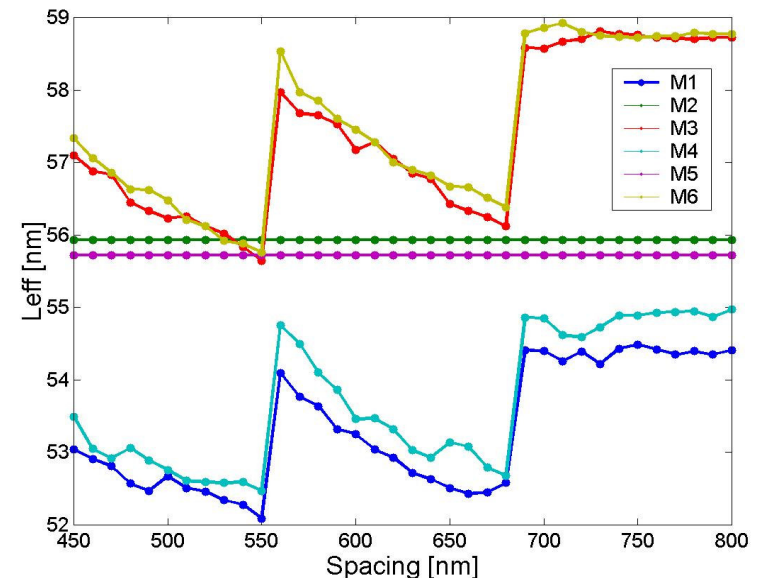
- Cells can be designed manually, and checked extensively using LPC tools.
  - Cell in must be printable!
  - Must be rock-solid building block



- But Gate Length Depends on Cell neighbors



- Living with it: cell de-rating
  - 5-10% impact on timing
  - 10-15% impact on leakage power
- Avoiding is much better:
  - Avoid by design **patterns** on standard cells
  - Certain detailed placement composability rules (conditional cell padding)

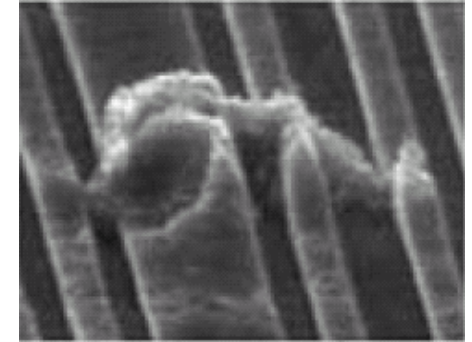


# Layout synthesis for Printability: score card

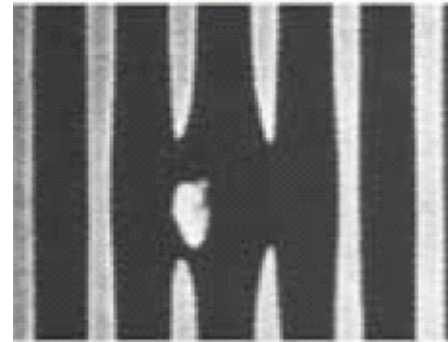
		The good	The bad
<b>Grid pre-conditioning</b>	<b>Hard Avoidance</b>	<b>Effective</b>	<b>Lower routability</b>
<b>No non-preferred</b>	<b>Hard Avoidance</b>	<b>Very effective fast</b>	<b>Routability, extra vias</b>
<b>Grid costing</b>	<b>Soft avoidance</b>	<b>Multiple objectives</b>	<b>Not very effective</b>
<b>Search patterns</b>	<b>Conditional avoidance</b>	<b>Effective</b>	<b>Slows down router</b>
<b>Post processing</b>	<b>Correction/ Patch-up</b>		<b>Slow, no guarantee</b>
<b>Standard cell design</b>	<b>Avoidance</b>	<b>Keeps abstraction</b>	<b>Pessimism, manual</b>

# Problem 3: Random layout yield loss

- **The problem is simple:**
  - Random particles cause opens and shorts, resulting in yield loss



- **Analysis tools:**
  - Predict (relative) yield using CAA that measures 'critical area'

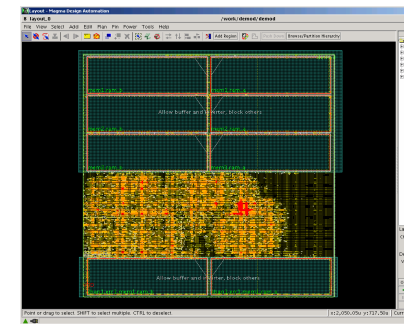
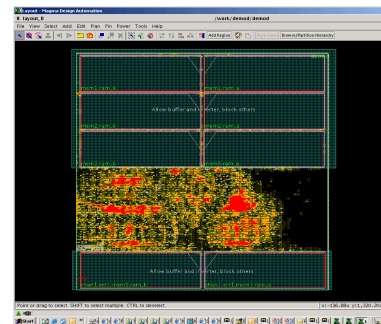


- **Synthesis mantra:**
  - Its OK to slip a few of these!

- **Issues:**
  - Trade-off between various factors nebulous

CAA before

CAA after



**MAGMA**

# Combating random yield loss

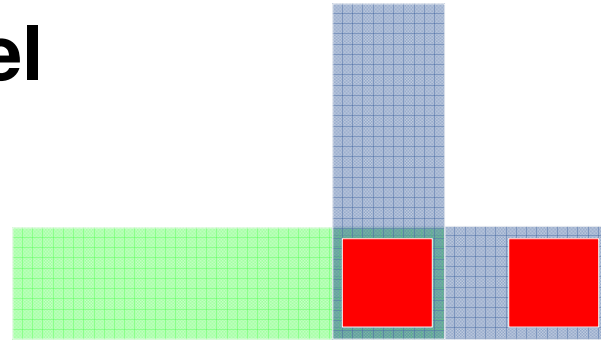
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- **Redundancy at system level**

- **Minimize contacts**

- **Make contacts redundant**

- >80% without drawbacks
- Most standard cell libraries are NOT redundant-via capable!!



- **Spread wires**

- Global routing
- During Detailed routing
- Using postprocessor

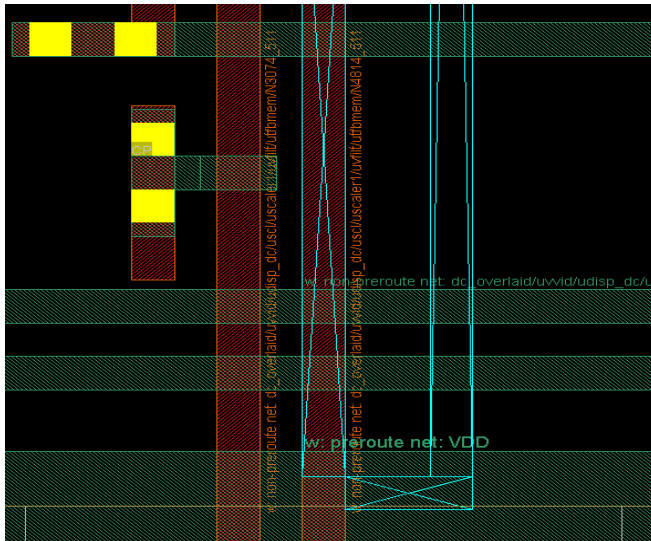
Assumes small defects dominate

- **Widen wires**

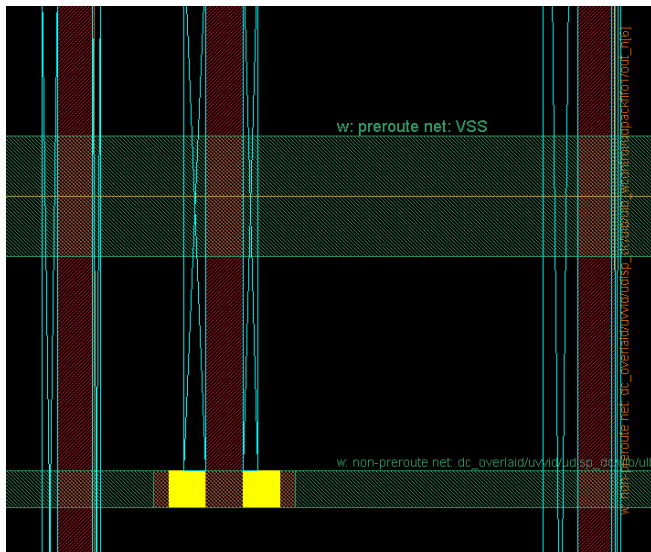
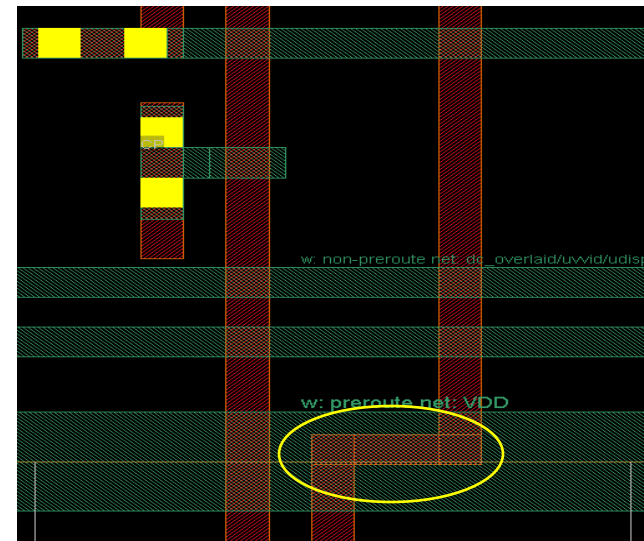
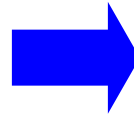
- Using postprocessor



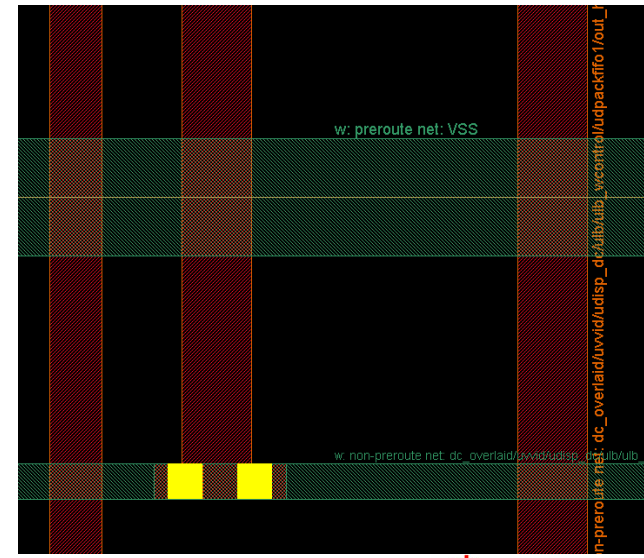
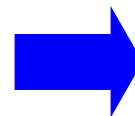
# Wire Spreading/Widening postprocessing



Wire Spreading



Wire Widening

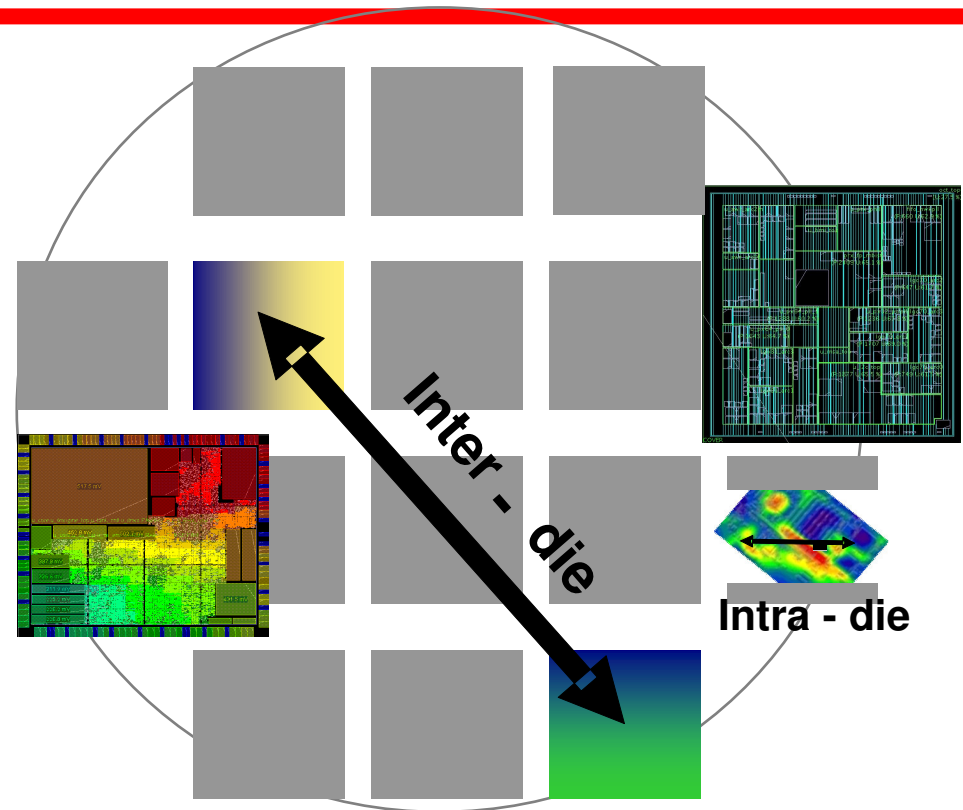


# Avoiding Random yield loss: scorecard

	Method	The good	The bad
Via reduction	Router costing	OK	Implies less spreading
Redundant vias	Post-process	Effective and Cheap	Last 10% are hard
Spreading	Global router costing		Longer wires, more vias
Spreading	Detailed router cost		Routability
Spreading	Post processing	Cheap	Longer wires
Widening	Post processing	Cheap	Forbidden pitch

# Other yield issues: parameter variation

- **Predictable:**
  - Temperature,
  - Voltage drop
- **Random:**
  - OCV
- **Attack plan:**
  - Reduce pessimism by back-annotating
  - Fast Multi-corner-multi-mode optimization
  - SSTA



# Quartz SSTA Analysis report

3 Console linux0827.magma-da.com:anardi:515

```
mantle[9]:> report statistical timing summary /work/basoc_top/basoc_top -noheader -number 40 -common 10
MSG-10 While running 'report statistical timing summary /work/basoc_top/basoc_top
-noheader -number 40 -common 10':
SSTA-18 Collecting 10000 critical paths for Monte-Carlo analysis
SSTA-19 Collected 10000 critical paths
SSTA-23 Using 183 paths after analytical path filtering
SSTA-20 Performing 1000 Monte-Carlo trials on collected paths
SSTA-21 Monte-Carlo analysis is done
```

Cell count 62994  
Node count 259523  
Event count 555994  
Endpoint count 29659  
Average late slack -106  
Mean late slack - 3sigma -173  
Sigma 22.4  
Parametric Yield 0.00

start point	end point	mean - Nsigma	mean slack	sigma	criticality	delay
#_iob17/en_out_reg/Q	#0[17]:out	-160	-72	29.4	15.8	2525
#g0/_ssp/Q[4]	#oad_reg/D	-202	-58	47.7	7.5	3765
#_iob16/en_out_reg/Q	#0[16]:out	-142	-55	29.2	7.1	2523
#_iob11/en_out_reg/Q	#0[11]:out	-141	-53	29.5	6.5	2524
#_iob10/en_out_reg/Q	#0[10]:out	-141	-53	29.5	6.5	2524
#_iob13/en_out_reg/Q	#0[13]:out	-141	-53	29.1	6.0	2523
#d_iob8/en_out_reg/Q	#I0[8]:out	-141	-53	29.5	5.9	2524
#_iob14/en_out_reg/Q	#0[14]:out	-141	-53	29.1	5.3	2523
#_iob15/en_out_reg/Q	#0[15]:out	-142	-55	29.2	5.2	2523

# Summary

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- **DFM&Y is a design problem!**
  - No single point solution, but a combination of methods
  - Delicate trade-off throughout flow:
    - Between avoidance and fix steps, and between other objectives
- **Keep GDS2 sign-off levels alive in 45nm!**
  - Cannot afford loops that involve slow analysis
  - Standard cells must remain rock-solid building blocks
  - Wires layout patterns must be restricted
- **0-order DFM wisdom for synthesis tools:**
  - Bigger cells = better
  - Lower density = better
  - Keep it regular and uniform
- **Must be 99.99% correct-by-construction**  
because iterative fixing is insecure and slow

